

Determination of Mineralogical Contents of a Bangle Shard from an Indus Valley Settlement through X-ray Diffraction Analysis

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The mineralogical make up of clay used in a bangle shard (Fig. 1) collected from Harrappa, an Indus Valley settlement now located in Pakistan has been determined using XRD testing carried out on 'Philips X'Pert PRO X-ray diffractometer' available in Geoscience Advance Research Laboratories (a facility of Geological Survey of Pakistan) in Islamabad. XRD analysis shows that the mineralogical make up includes montmorillonite ($(\text{Na}, \text{Ca})_{0.33}(\text{Al}, \text{Mg})_2(\text{Si}_4\text{O}_{10})(\text{OH})_2 \cdot n\text{H}_2\text{O}$), gypsum ($\text{CaSO}_4 \cdot 2\text{H}_2\text{O}$), and quartz (SiO_2). The X-ray diffractogram was developed using PW3050/60 goniometer. The generator settings were 30 mA/40 kV with $\text{CuK}\alpha$ radiation of $\lambda = 1.5406 \text{ \AA}$. Continuous scanning was carried out from 10.01 as 2 θ start position to 79.99 as 2 θ end position, with a step size of 0.02 and step time of 1 s.



Fig. 1 Bangle shard photographed with Pakistani one rupee coin as reference. Diameter: 0.95-1 cm, length: 5.65 cm or about 2/5th of the complete bangle.

XRD Testing Parameters and Results

1(a) Anchor Scan Parameters

Dataset Name:

H-1

File Name:

C:\X'Pert Data\2011\May\H-1.xrdml

Comment:

Material analysis for universities

Configuration=Flat Sample Stage, Owner=User-1, Creation date=2/5/2008 9:32:46 AM

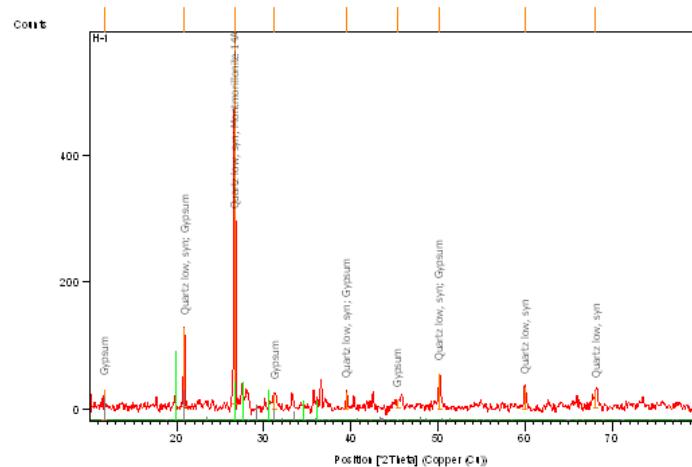
Goniometer=PW3050/60 (Theta/Theta); Minimum step size 2Theta:0.001; Minimum step size Omega:0.001

Sample stage=PW3071/xx Bracket

Diffractometer system=XPERT-PRO
 Measurement program=material analysis, Owner=User-1, Creation date=3/28/2008 10:27:40 AM
 synthetic material

Measurement Date / Time: 5/6/2011 9:25:21 PM
 Operator: Geoscience
 Raw Data Origin: XRD measurement (*.XRDML)
 Scan Axis: Gonio
 Start Position [°2Th.]: 10.0100
 End Position [°2Th.]: 79.9900
 Step Size [°2Th.]: 0.0200
 Scan Step Time [s]: 1.0000
 Scan Type: Continuous
 Offset [°2Th.]: 0.0000
 Divergence Slit Type: Fixed
 Divergence Slit Size [°]: 0.5000
 Specimen Length [mm]: 10.00
 Receiving Slit Size [mm]: 0.1000
 Measurement Temperature [°C]: 25.00
 Anode Material: Cu
 K-Alpha1 [Å]: 1.54060
 K-Alpha2 [Å]: 1.54443
 K-Beta [Å]: 1.39225
 K-A2 / K-A1 Ratio: 0.50000
 Generator Settings: 30 mA, 40 kV
 Diffractometer Type: 0000000011037156
 Diffractometer Number: 0
 Goniometer Radius [mm]: 240.00
 Dist. Focus-Diverg. Slit [mm]: 100.00
 Incident Beam Monochromator: No
 Spinning: No

1(b) Graphics

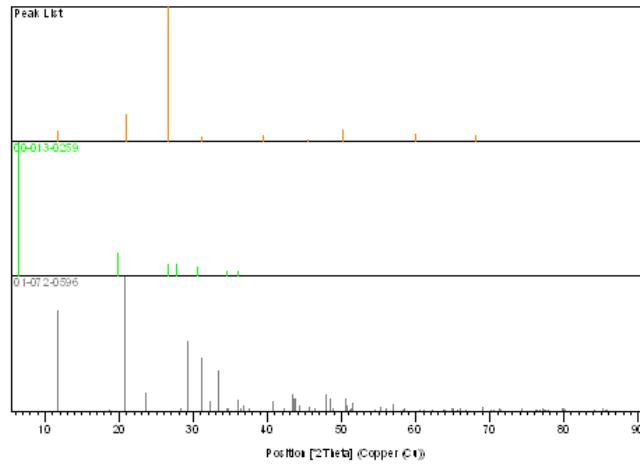


2(a) Peak List

Pos.[$^{\circ}$ 2Th.]	Height[cts]	FWHM[$^{\circ}$ 2Th.]	d-spacing[\AA]	Rel.Int.[%]	Tipwidth[$^{\circ}$ 2Th.]	Matched by
11.6307	48.56	0.0150	7.60871	8.23	0.0180	01-072-0596
20.8542	124.13	0.1771	4.25968	21.05	0.2125	03-065-0466;01..
26.6610	589.75	0.1968	3.34364	100.00	0.2362	03-065-0466;00..
31.2494	25.46	0.4723	2.86237	4.32	0.5668	01-072-0596
39.5060	28.61	0.2362	2.28111	4.85	0.2834	03-065-0466;01..
45.3856	11.54	0.9446	1.99833	1.96	1.1336	01-072-0596
50.2031	55.70	0.1968	1.81729	9.44	0.2362	03-065-0466;01..
59.9984	35.04	0.2362	1.54191	5.94	0.2834	03-065-0466
68.1453	27.77	0.5760	1.37494	4.71	0.6912	03-065-0466

2(b) Pattern List

Visible	Ref. Code	Score	Compound Name	Displ.[$^{\circ}$ 2Th]	Scale Fac.	Chem. Formula
	03-065-0466	72	Quartz low, syn	0.000	0.962	SiO2
*	00-013-0259	5	Montmorillonite-14A	0.000	9.948	Na0.3(Al,Mg)2..
*	01-072-0596	11	Gypsum	0.000	0.077	Ca(SO4)(H2O)..



2(c) Graphics